LT3310 Substage

Our range of stages are suited for orthogonal positioning solutions in atmosphere, SEM/FIB, UHV and at low temperatures.

The LT₃₃₁₀ is primarily used in SEM/FIB to enhance the accuracy and functionality of the standard microscope stage. Its smooth motion and rotational axis make it ideal for cell counting. In addition, the LT₃₃₁₀ is designed for nanomanipulation applications where weight and space are highly restricted and for high-precision work in extreme environments.



APPLICATIONS

Substage for SEM & FIB

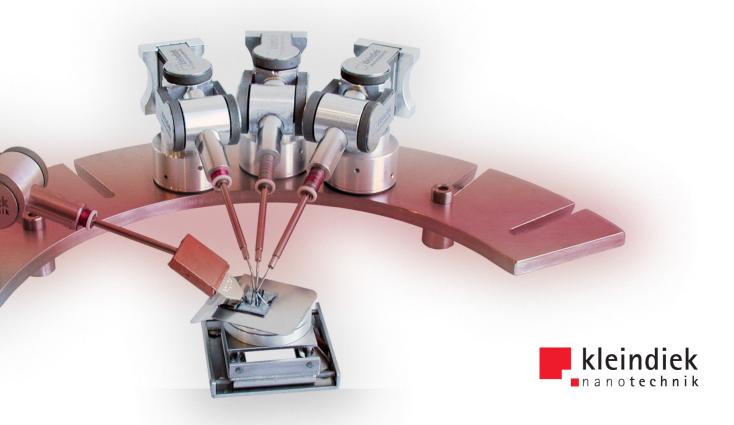
Cell counting

Particle counting

CUSTOMIZATION

Two or three linear axes

- Rotational axis
- Ultra high vacuum compatible
- Low temperature compatible
- Non-magnetic material



LT3310 Substage

More compact and more flexible

- Small and practical
- Plug-and-play system with modular design
- Interfacing solutions for most SEM/FIB instruments (including load lock)
- Fast setup and removal

Clearer and simpler

- Result-oriented operation which leads to increased throughput
- Intuitive control interfaces, user-friendly software and API support
- User-friendly and easy to learn
- Compact, stand-alone electronics
- Pioneering cabling technology with compact vacuum feedthrough

More robust and more stable

- Compact construction delivers higher resonance frequencies
- Excellent stability
- Virtually insusceptible to vibrations
- Reliable operation (one year endurance test)
- Fast pre-positioning by hand
- Functions in extreme working environments

Faster and more precise

- No backlash or reversal play
- Sub-nanometer resolution (< 0.5 nm)
- Coarse and fine displacement in one drive
- High operating velocity (up to 1 mm/sec)
- Low drift (1 nm/min)
- Smooth motion

Technical specifications

- Length 33 mm
- Width 33 mm
- X,Y = HORIZONTAL Z = VERTICAL R = HORIZ. ROTATION
- Width 55 min
- Height XY 11.6 mm
 Height XYZ 30 mm + 7 mm travel
 Height XYR 16.6 mm
- Weight XY 22 g
 Weight XYZ 34 g
 Weight XYR 27 g
- Travel XY 10 mm
 Travel Z 7 mm
 Travel R 360° unlimited
- Speed up to 1 mm/s
- Resolution XYZ < 0.02 nm Resolution R 10⁻⁷ rad
- Load 50 g
- Lift 25 g
- Maximum sample size 25 mm × 25 mm
- Temperature range 273 K to 353 K UHV version 273 K to 393 K
- Lowest pressure 10⁻⁷ mbar
 UHV version 2 × 10⁻¹⁰ mbar
- Substage mounting 4 × 2 mm holes
- Sample mounting 4 × M2 holes
- Material Stainless steel

Contact us at info@kleindiek.com or find your local agent at www.kleindiek.com

